

Notice of References Cited

Application/Control No.

10/743,956

Applicant(s)/Patent Under
Reexamination
CHEN ET AL.

Examiner

Christopher M. Gross

Art Unit

1639

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2006/0252114	11-2006	RayChaudhuri et al.	435/032
	B	US-			
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	D	US-			
	E	US-			
	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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	N	EP 1 108 790 A2	06-2001	Europe	Nakagawa et al	
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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